

<b>Notice of References Cited</b>	Application/Control No. <div style="text-align: center;"><b>09/642,052</b></div>		Applicant(s)/Patent Under Reexam <div style="text-align: center;"><b>Lapalme</b></div>	
	Examiner <div style="text-align: center;"><b>Richard Lee</b></div>		Art Unit <div style="text-align: center;"><b>2613</b></div>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Name	Classification <sup>2</sup>	
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B	5,884,197	3/1999	Ricardo et al	455	575
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a). <sup>1</sup> Dates in MM-YYYY format are publication dates. <sup>2</sup> Classifications may be U.S. or foreign.